COOPERATIVE PATENT CLASSIFICATION

G   PHYSICS
    (NOTES omitted)

INSTRUMENTS

G01   MEASURING; TESTING
    (NOTES omitted)

G01R   MEASURING ELECTRIC VARIABLES; MEASURING MAGNETIC VARIABLES
(measuring physical variables of any kind by conversion into electric variables, see Note (4) following the title of class G01; measuring diffusion of ions in an electric field, e.g. electrophoresis, electro-osmosis G01N; investigating non-electric or non-magnetic properties of materials by using electric or magnetic methods G01N; indicating correct tuning of resonant circuits H03J 3/12; monitoring electronic pulse counters H03K 21/40; monitoring operation of communication systems H04)

NOTES
1. This subclass covers:
   • measuring all kinds of electric or magnetic variables directly or by derivation from other electric or magnetic variables;
   • measuring all kinds of electric or magnetic properties of materials;
   • testing electric or magnetic devices, apparatus or networks, (e.g. discharge tubes, amplifiers) or measuring their characteristics;
   • indicating presence or sign of current or voltage;
   • NMR, EPR or other spin-effect apparatus, not specially adapted for a particular application;
   • equipment for generating signals to be used for carrying out such tests and measurements.
2. In this subclass, the following terms or expressions are used with the meanings indicated:
   • “measuring” includes investigating;
   • “instruments” or “measuring instruments” means electro-mechanical measuring mechanisms;
   • “arrangements for measuring” means apparatus, circuits, or methods for measuring;
3. Attention is drawn to the Notes following the title of class G01.
4. In this subclass, group G01R 17/00 takes precedence over groups G01R 19/00 - G01R 31/00.

WARNING
In this subclass non-limiting references (in the sense of paragraph 39 of the Guide to the IPC) may still be displayed in the scheme.

1/00 Details of instruments or arrangements of the types included in groups G01R 5/00 - G01R 13/00 and G01R 31/00 (constructional details particular to [electromechanical] arrangements for measuring the electric consumption G01R 11/02)
1/02 . General constructional details (details of a kind applicable to measuring arrangements not specially adapted for a specific variable G01D 7/00)
1/025 . . {concerning dedicated user interfaces, e.g. GUI, or dedicated keyboards (G01R 31/31912 takes precedence)}
1/04 . . Housings; Supporting members; Arrangements of terminals (“burn-in” aspects G01R 31/286; terminals H01R; terminal strips or boards H02B; housings for electrical apparatus H05K)
1/0408 . . . {Test fixtures or contact fields; Connectors or connecting adaptors; Test clips; Test sockets (G01R 1/067 takes precedence; mass production testing systems G01R 31/59; testing of connections G01R 31/66; for testing printed circuit boards G01R 31/2808)}
1/0416 . . . {Connectors, terminals (G01R 1/0425 and G01R 1/0433 take precedence; with measurement function for battery poles G01R 31/364)}
1/0425 . . . {Test clips, e.g. for IC’s}
1/0433 . . . {Sockets for IC’s or transistors}
1/0441 . . . . {Details}
1/045 . . . . {Sockets or component fixtures for RF or HF testing}
1/0458 . . . . {related to environmental aspects, e.g. temperature}
1/0466 . . . . {concerning contact pieces or mechanical details, e.g. hinges or cams; Shielding}
1/0475 . . . . {for TAB IC’s}
1/0483 . . . . {Sockets for un-leaded IC’s having matrix type contact fields, e.g. BGA or PGA devices; Sockets for unpackaged, naked chips (for IC’s with connecting points around the edges only G01R 1/0433)}
1/067 . . . . Measuring probes (plugs, sockets or clips G01R 1/0408; testing of connections G01R 31/66; contacting IC’s for test purposes when probe design is not the essential feature G01R 31/2886; using radiation beam as probe G01R 31/302; end pieces for wires terminating in a probe H01R 11/18)

1/06705 . . . . [Apparatus for holding or moving single probes (for moving multiple probe heads or ICs under test G01R 31/2886)]

1/06711 . . . . [Probe needles; Cantilever beams; "Bump" contacts; Replaceable probe pins]

1/06716 . . . . [Elastic]

1/06722 . . . . [Spring-loaded]

1/06727 . . . . [Cantilever beams]

WARNING
This group is not complete pending a reorganisation; see also other subgroups of G01R 1/06711

1/06733 . . . . [Geometry aspects (G01R 1/06727 takes precedence)]

1/06738 . . . . [related to tip portion]

1/06744 . . . . [Microprobes, i.e. having dimensions as IC details]

1/0675 . . . . [Needleprobes]

1/06755 . . . . [Material aspects]

1/06761 . . . . [related to layers]

1/06766 . . . . [Input circuits therefor]

1/06772 . . . . [High frequency probes]

1/06777 . . . . [High voltage probes]

1/06783 . . . . [containing liquids]

1/06788 . . . . [Hand-held or hand-manipulated probes, e.g. for oscilloscopes or for portable test instruments (end pieces terminating in a probe H01R 11/18)]

1/06794 . . . . [Devices for sensing when probes are in contact, or in position to contact, with measured object]

1/07 . . . . Non-contact-making probes (wireless interface with the DUT G01R 31/3025)

1/071 . . . . [containing electro-optic elements]

1/072 . . . . [containing ionised gas]

1/073 . . . . Multiple probes (G01R 1/06783, G01R 1/06794, G01R 1/071, G01R 1/072 take precedence)

1/07307 . . . . [with individual probe elements, e.g. needles, cantilever beams or bump contacts, fixed in relation to each other, e.g. bed of nails fixture or probe card]

1/07314 . . . . [the body of the probe being perpendicular to test object, e.g. bed of nails or probe with bump contacts on a rigid support (on an elastic support, e.g. a film, G01R 1/0735)]

1/07321 . . . . [the probes being of different lengths]

1/07328 . . . . [for testing printed circuit boards]
Instruments employing mechanical resonance

9/00

9/02 . Vibration galvanometers, e.g. for measuring current
9/04 . using vibrating reeds, e.g. for measuring frequency
9/06 . magnetically driven

9/08 . piezo-electrically driven

11/00 Electro-mechanical arrangements for measuring time integral of electric power (i.e. electric energy) or current, e.g. of consumption (other arrangements for measuring time integral of electric power or current G01R 22/00; boards, panels, desks for energy meters, H02B 1/03; monitoring electric consumption of electrically-propelled vehicles B60L 3/00)

NOTE
For the definition of "arrangement" see Note (2) under G01R

11/02 . Constructional details (applicable to electric measuring instruments in general G01R 1/00)
11/04 . Housings; Supporting racks; Arrangements of terminals
11/06 . Magnetic circuits of induction meters
11/07 . Coils therefor
11/09 . Disc armatures
11/10 . Braking magnets; Damping arrangements
11/12 . Arrangements of bearings (bearings in general F16C)
11/14 . with magnetic relief
11/16 . Adaptations of counters to electricity meters
11/17 . Compensating for errors; Adjusting or regulating means therefor
11/18 . Compensating for variations in ambient conditions
11/185 . Temperature compensation
11/19 . Compensating for errors caused by disturbing torque, e.g. rotating-field errors of polyphase meters
11/20 . Compensating for phase errors in induction meters
11/21 . Compensating for errors caused by damping effects of the current, e.g. adjustment in the overload range
11/22 . Adjusting torque, e.g. adjusting starting torque, adjusting of polyphase meters for obtaining equal torques
11/23 . Compensating for errors caused by friction, e.g. adjustment in the light load range
11/24 . Arrangements for avoiding or indicating fraudulent use (measures against unauthorised operation of bolts, nuts or pins F16B 41/005; security seals G09F 3/03; preventing of tampering with detection circuits in signaling or alarm circuits G08B 29/046)

11/25 . Arrangements for indicating or signalling faults (seals G09F 3/03; preventing tampering with detection circuits in signaling or alarm circuits G08B 29/046)

NOTE
Groups G01R 11/48 - G01R 11/66 take precedence over groups G01R 11/30 - G01R 11/46.

11/30 . Dynamo-electric motor meters
11/32 . Watt-hour meters
11/34 . Ampere-hour meters
11/36 . Induction meters, e.g. Ferraris meters (Ferraris instruments G01R 5/20)
11/38 . for single-phase operation
11/40 . for polyphase operation
11/42 . Circuitry therefor
11/46 . Electrically-operated clockwork meters; Oscillatory meters; Pendulum meters
11/465 . (Oscillatory meters)
11/48 . Meters specially adapted for measuring real or reactive components; Meters specially adapted for measuring apparent energy
11/50 . for measuring real component
11/52 . for measuring reactive component
11/54 . for measuring simultaneously at least two of the following three variables: real component, reactive component, apparent energy
11/56 . Special tariff meters (tariff metering in general G01D 4/00)
11/57 . Multi-rate meters (G01R 11/63 takes precedence)
11/58 . Tariff-switching devices therefor
11/60 . Subtraction meters; Meters measuring maximum or minimum load hours
11/63 . Over-consumption meters, e.g. measuring consumption while a predetermined level of power is exceeded
11/64 . Maximum meters, e.g. tariff for a period is based on maximum demand within that period
11/66 . Circuitry
13/00 Arrangements for displaying electric variables or waveforms (display by mechanical displacement only G01R 5/00; G01R 7/00; G01R 9/00; recording frequency spectrum G01R 23/18)
13/02 . for displaying measured electric variables in digital form (using LCD's or LED's G01R 13/40; counters G06M; analogue/digital conversion in general H03M 1/00)
13/0209 . (in numerical form)
13/0218 . (Circuits therefor)
13/0227 . [Controlling the intensity or colour of the display]
13/0236 . [for presentation of more than one variable]
13/0245 . [for inserting reference markers]
13/0254 . [for triggering, synchronisation]
13/0263 . [for non-recurrent functions, e.g. transients]
13/0272 . [for sampling]
13/0281 . [using electro-optic elements]
13/029 . [Software therefor]
13/04 . for producing permanent records
13/06 . Modifications for recording transient disturbances, e.g. by starting or accelerating a recording medium
13/08 . Electromechanical recording systems using a mechanical direct-writing method
13/10 . with intermittent recording by representing the variable by the length of a stroke or by the position of a dot
13/12 . Chemical recording, e.g. clydonographs (G01R 13/14 takes precedence)
13/14 . Recording on a light-sensitive material
13/16 . Recording on a magnetic medium
13/18 . using boundary displacement
13/20 . Cathode-ray oscilloscopes [; Oscilloscopes using other screens than CRT's, e.g. LCD's; (control arrangements or circuits for cathode-ray tube indicators G09G 1/00; cathode ray tubes H01J 31/00)]
13/202 . [Non-electric appliances, e.g. scales, masks (luminescents screens for CRT provided with permanent marks or references H01J 29/24; optical or photographic arrangements combined with CRT vessels H01J 29/95)]
13/204 . [Using means for generating permanent registrations, e.g. photographs (optical or photographic arrangements combined with CRT vessel H01J 29/95)]
13/206 . [Arrangements for obtaining a 3-dimensional representation (stereoscopic T.V. H04N 13/00)]
13/208 . [Arrangements for measuring with C.R. oscilloscopes, e.g. vectorscope]
13/22 . Circuits therefor (circuits for generating pulses, e.g. saw-tooth waveforms H03K 3/00)
13/225 . [particularly adapted for storageoscilloscopes]
13/228 . Time-base deflection circuits
13/245 . (for generating more than one, not overlapping time-intervals on the screen)
13/26 . Circuits for controlling the intensity of the electron beam [or the colour of the display] (brilliance control H01J 29/98)
13/28 . Circuits for simultaneous or sequential presentation of more than one variable (electronic switches H03K 17/00)
13/30 . Circuits for inserting reference markers, e.g. for timing, for calibrating, for frequency marking
13/305 . { for time marking}
13/32 . Circuits for displaying non-recurrent functions such as transients; Circuits for triggering; Circuits for synchronisation; Circuits for time-base expansion
13/325 . { for displaying non-recurrent functions such as transients]
13/34 . Circuits for representing a single waveform by sampling, e.g. for very high frequencies (sample and hold arrangements G11C 27/02)
13/342 . { for displaying periodic H.F. signals (G01R 13/345 takes precedence)}
13/345 . { for displaying sampled signals by using digital processors by intermediate A.D. and D.A. converters (control circuits for CRT indicators])
13/347 . { using electro-optic elements]
13/36 . using length of glow discharge, e.g. glowlight oscilloscopes (discharge tubes H01J)
13/38 . using the steady or oscillatory displacement of a light beam by an electromechanical measuring system (such measuring systems per se G01R 5/00, G01R 7/00, G01R 9/00)
13/40 . using modulation of a light beam otherwise than by mechanical displacement, e.g. by Kerr effect (visual indication of correct tuning H03J 3/14)
13/401 . [for continuous analogue, or simulated analogue, display]
13/402 . [using active, i.e. light-emitting display devices, e.g. electroluminescent display (G01R 13/36 and G01R 13/42 take precedence)]
13/403 . . . [using passive display devices, e.g. liquid crystal display or Kerr effect display devices]
13/404 . . . [for discontinuous display, i.e. display of discrete values (analogue/digital conversion H03M 1/00)]
13/405 . . . [using a plurality of active, i.e. light emitting, e.g. electro-luminescent elements, i.e. bar graphs]
13/406 . . . [representing measured value by a dot or a single line (G01R 13/408 takes precedence)]
13/407 . . . [using a plurality of passive display elements, e.g. liquid crystal or Kerr-effect display elements (G01R 13/408 takes precedence)]
13/408 . . . [Two or three dimensional representation of measured values]
13/42 . . . Instruments using length of spark discharge, e.g. by measuring maximum separation of electrodes to produce spark

15/00 Details of measuring arrangements of the types provided for in groups G01R 17/00 - G01R 29/00 and G01R 33/00 - G01R 35/00 (details of instruments G01R 1/00; overload protection arrangements G01R 1/36)
15/002 . . . [Switches for altering the measuring range or for multimeters]
15/005 . . . [Circuits for altering the indicating characteristic, e.g. making it non-linear]
15/007 . . . [by zero-suppression]
15/04 . . . Voltage dividers
15/06 . . . having reactive components, e.g. capacitive transformer ([when the HV capacitor/sensor as such is the essential G01R 15/16])
15/08 . . . Circuits for altering the measuring range
15/09 . . . Autoranging circuits
15/12 . . . Circuits for multi-testers [. i.e. multimeters], e.g. for measuring voltage, current, or impedance at will
15/125 . . . [for digital multimeters]
15/14 . . . Adaptations providing voltage or current isolation, e.g. for high-voltage or high-current networks (instrument transformers H01F 38/20; voltage dividers G01R 15/04; [means for converting the output of a sensing member to another variable G01D 5/00; visible signalling arrangements or devices G08B 5/00; transmission systems for measured values G08C 17/00, G08C 23/00])
15/142 . . . [Arrangements for simultaneous measurements of several parameters employing techniques covered by groups G01R 15/14 - G01R 15/26]
15/144 . . . [Measuring arrangements for voltage not covered by other subgroups of G01R 15/14]
15/146 . . . [Measuring arrangements for current not covered by other subgroups of G01R 15/14; e.g. using current dividers, shunts, or measuring a voltage drop (if no voltage isolation is involved G01R 1/203 or G01R 19/092)]
15/148 . . . [involving the measuring of a magnetic field or electric field (G01R 15/18, G01R 15/20, G01R 15/24, G01R 15/26 take precedence)]
15/16 . . . using capacitive devices ([circuits constituting a voltage divider G01R 15/06])
15/165 . . . [measuring electrostatic potential, e.g. with electrostatic voltmeters or electroimeters, when the design of the sensor is essential (electrometers with passively moving electrodes G01R 5/28; measuring electrostatic fields G01R 29/12; measuring charge G01R 29/24; measuring in circuits with high internal resistance G01R 19/0023)]
15/18 . . . using inductive devices, e.g. transformers
15/181 . . . [using coils without a magnetic core, e.g. Rogowski coils]
15/183 . . . [using transformers with a magnetic core]
15/185 . . . [with compensation or feedback windings or interacting coils, e.g. 0-flux sensors (using galvo-magnetic field sensors G01R 15/20; conversion of DC into AC using transducers G01R 19/20)]
15/186 . . . [using current transformers with a core consisting of two or more parts, e.g. clamp-on type (G01R 15/142 - G01R 15/16 take precedence; tong testers G01R 1/22)]
15/188 . . . [comprising rotatable parts, e.g. moving coils (galvanometers G01R 5/02, G01R 5/14)]
15/20 . . . using galvo-magnetic devices, e.g. Hall-effect devices [. i.e. measuring a magnetic field via the interaction between a current and a magnetic field, e.g. magneto resistive or Hall effect devices (electromechanical such devices, G01R 5/00, G01R 7/00, G01R 9/00; measuring magnetic fields G01R 33/02)]
15/202 . . . [using Hall-effect devices (Hall elements in arrangements for measuring electrical power G01R 21/08)]
15/205 . . . [using magneto-resistance devices, e.g. field plates]
15/207 . . . [Constructional details independent of the type of device used]
15/22 . . . using light-emitting devices, e.g. LED, optocouplers {G01R 31/3101 takes precedence}
15/24 . . . using light-modulating devices
15/241 . . . [using electro-optical modulators, e.g. electro-absorption (probes containing electro-optic elements G01R 1/071)]
15/242 . . . [based on the Pockels effect, i.e. linear electro-optic effect]
15/243 . . . [based on the Kerr effect, i.e. quadratic electro-optic effect]
15/245 . . . [using magneto-optical modulators, e.g. based on the Faraday or Cotton-Mouton effect]
15/246 . . . [based on the Faraday, i.e. linear magneto-optic, effect]
15/247 . . . [Details of the circuitry or construction of devices covered by G01R 15/241 - G01R 15/246]
15/248 . . . [using a constant light source and electromechanically driven deflectors]
15/25 . . . using modulation of waves other than light, e.g. radio or acoustic waves

17/00 Measuring arrangements involving comparison with a reference value, e.g. bridge
17/02 . . . Arrangements in which the value to be measured is automatically compared with a reference value
Arrangements for measuring currents or voltages or for indicating presence or sign thereof (G01R 5/00 takes precedence; [voltage measurements using secondary electron emission when testing electronic circuits G01R 31/305]; for measuring bioelectric currents or voltages A61B 5/04)

NOTE

Within groups G01R 19/02 - G01R 19/32, group G01R 19/28 takes precedence. Groups G01R 19/18 - G01R 19/247 take precedence over groups G01R 19/02 - G01R 19/17 and G01R 19/30.

19/0007 . . . [Frequency selective voltage or current level measuring (measuring frequency G01R 23/00; testing attenuation in line transmission systems H04B 3/48; monitoring testing in transmission systems H04B 17/00)]

19/0015 . . . [separating AC and DC]

19/0023 . . . [Measuring currents or voltages from sources with high internal resistance by means of measuring circuits with high input impedance, e.g. OP-amplifiers (electrostatic instruments G01R 5/28; measuring electrostatic potential G01R 15/165; measuring electrostatic fields G01R 29/12; amplifiers per se H03F)]

19/003 . . . [Measuring mean values of current or voltage during a given time interval]

19/0038 . . . [Circuits for comparing several input signals and for indicating the result of this comparison, e.g. equal, different, greater, smaller (comparing pulses or pulse trains according to amplitude)]

19/0046 . . . [characterised by a specific application or detail not covered by any other subgroup of G01R 19/00]

19/0053 . . . [Noise discrimination; Analog sampling; Measuring transients (measuring characteristics of individual pulses G01R 29/02; digital sampling G01R 19/2509; measuring noise figure G01R 29/26)]

19/0061 . . . [Measuring currents of particle-beams, currents from electron multipliers, photocurrents, ion currents; Measuring in plasmas]

19/0069 . . . [measuring voltage or current standards]

19/0076 . . . [using thermionic valves]

19/0084 . . . [measuring voltage only (all subgroups of G01R 19/00 take precedence)]

19/0092 . . . [measuring current only (all subgroups of G01R 19/00 take precedence)]

19/02 . . . [Measuring effective values, i.e. root-mean-square values]

19/03 . . . [using thermoconverters {using ac-dc conversion by means of thermocouples or other heat sensitive elements G01R 19/225}]

19/04 . . . [Measuring peak values {or amplitude or envelope} of ac or of pulses]

19/06 . . . [Measuring real component; Measuring reactive component]

19/08 . . . [Measuring current density]

19/10 . . . [Measuring sum, difference or ratio]

19/12 . . . [Measuring rate of change {emergency protective circuit arrangements responsive to the rate of change of electrical quantities H02H 3/44}]

19/14 . . . [Indicating direction of current; Indicating polarity of voltage]

19/145 . . . [Indicating the presence of current or voltage (measuring probes in general G01R 1/06; indicating continuity or short circuits in electric apparatus or lines or components G01R 31/50)]

19/15 . . . [Indicating the presence of current (see provisionally also G01R 19/145)]

19/155 . . . [Indicating the presence of voltage (see provisionally also G01R 19/145)]

19/165 . . . [Indicating that current or voltage is either above or below a predetermined value or within or outside a predetermined range of values (circuits with regenerative action, e.g. Schmitt trigger H03K 3/00; threshold switches H03K 17/00)]

19/16504 . . . [characterised by the components employed]

19/16509 . . . [using electromagnetic relays, e.g. reed relay (magnetically driven reeds G01R 9/06)]

19/16514 . . . [using electronic tubes]

19/16519 . . . [using FET's]

19/16523 . . . [using diodes, e.g. Zener diodes]

19/16528 . . . [using digital techniques or performing arithmetic operations (using digital techniques to measure a voltage or a current, see G01R 19/25)]

19/1653 . . . [characterised by the application]

19/16538 . . . [in AC or DC supplies (G01R 19/16519 and G01R 19/16528 take precedence)]

19/16542 . . . [for batteries (charge condition monitoring in G01R 31/36)]

19/16547 . . . [voltage or current in AC supplies (switching for protection H02H; circuits for emergency power supply H02J 9/00)]

19/16552 . . . [in L.C. power supplies]

19/16557 . . . [Logic probes, i.e. circuits indicating logic state (high, low, O); (modifications of electronic switches or gates for indicating state of switch H03K 17/18)]

19/16561 . . . [in hand-held circuit testers (see also G01R 19/155)]
{Circuits and arrangements for comparing voltage or current with one or several thresholds and for indicating the result not covered by subgroups G01R 19/16504, G01R 19/16528, G01R 19/16533.}

{Comparing AC or DC current with one threshold, e.g. load current, over-current, surge current or fault current (G01R 19/16514, G01R 19/16519, G01R 19/16528, G01R 19/16533; G01R 19/1659 take precedence; measuring currents by using elements sensitive to the magnetic field generated G01R 15/14; measuring earth resistance G01R 27/18; testing for leakage or short circuits in electrical apparatus G01R 31/52).}

{Comparing DC or AC voltage with one threshold (G01R 19/16514, G01R 19/16519, G01R 19/16528, G01R 19/16533 and G01R 19/1659 take precedence).}

{AC voltage or recurrent signals.}

{for individual pulses, ripple or noise and other applications where timing or duration is of importance (G01R 19/16519, G01R 19/16538 and G01R 19/16595 take precedence; for pulse duration and rise time, see G01R 29/02 and subgroups).}

{to indicate that the value is within or outside a predetermined range of values (window) (G01R 19/16514, G01R 19/16519, G01R 19/16528 and G01R 19/16533 take precedence).}

{with multi-level indication (G01R 19/16519 and G01R 19/16533 take precedence).}

{Giving an indication of the number of times this occurs, i.e. multi-channel analysers.}

{Indicating the instants of passage of current or voltage through a given value, e.g. passage through zero.}

{using conversion of dc into ac, e.g. with choppers (DC amplifiers with modulators at input and demodulator at output H03F 3/38).}

{using transductors, i.e., a magnetic core transducer the saturation of which is cyclically reversed by an AC source on the secondary side; other DC current transducers, e.g. using the 0-flux principle; G01R 15/185; magnetic amplifiers H03F 9/00).}

{using conversion of ac into dc.}

{by means of thermocouples or other heat sensitive elements.}

{[Circuits and arrangements for converting measured electric variables in digital form G01R 13/02 (Analog-to-digital conversion H03M)].}

{Digital measurement techniques (arrangements for displaying measured electric variables in digital form G01R 13/02) (Analog-to-digital conversion H03M).}

{for measuring voltage only, e.g. digital volt meters (DVMs) (G01R 19/2506 - G01R 19/257 take precedence).}

{Arrangements for conditioning or analysing measured signals, e.g. for indicating peak values (G01R 19/003 takes precedence); Details concerning sampling, digitizing or waveform capturing (displaying waveforms G01R 13/00; analog sampling G01R 19/0053).}

{Details concerning sampling, digitizing or waveform capturing.}

{Arrangements for monitoring electric power systems, e.g. power lines or loads; Logging.}

{Modular arrangements for computer based systems; using personal computers (PC's), e.g. “virtual instruments”.

{using analogue/digital converters of the type with conversion of voltage or current into frequency and measuring of this frequency.

{using analogue/digital converters of the type with counting of pulses during a period of time proportional to voltage or current, delivered by a pulse generator with fixed frequency.

{using analogue/digital converters of the type with comparison of different reference values with the value of voltage or current, e.g. using step-by-step method.

{adapted for measuring in circuits having distributed constants.

{Measuring the maximum or the minimum value of current or voltage reached in a time interval (G01R 19/04 takes precedence; modifications of instruments to indicate the maximum or the minimum value reached in a time interval G01R 1/40; (using digital methods G01R 19/2506)).

{Compensating for temperature change (G01R 19/02 - G01R 19/30 take precedence; modifications of instruments for temperature compensation G01R 1/44).}

{Arrangements for measuring electric power or power factor (G01R 7/12 takes precedence).}

{Measuring real or reactive component; Measuring apparent energy (G01R 21/01, G01R 21/02, G01R 21/08, G01R 21/10 and G01R 21/122 take precedence).}

{Measuring real component.}

{Measuring reactive component.}

{Measuring apparent power.}

{Measuring power factor.}

{Adapted for special tariff measuring (G01R 21/01, G01R 21/02, G01R 21/08, G01R 21/10, G01R 21/1275 and G01R 21/1333 take precedence).}

{Measuring maximum demand.}

{in circuits having distributed constants (G01R 21/04, G01R 21/07, G01R 21/09, G01R 21/12 take precedence).}

{by thermal methods, e.g. calorimetric.}

{in circuits having distributed constants.}

{by measuring current and voltage (G01R 21/08 - G01R 21/133 take precedence).}

{in circuits having distributed constants (G01R 21/09 takes precedence).}

{by using galvanomagnetic effect devices, e.g. Hall effect devices (such devices per se H01L; for current measurements only, see G01R 15/20).}

{in circuits having distributed constants.}

{by using square-law characteristics of circuit elements, e.g. diodes, to measure power absorbed by loads of known impedance (G01R 21/02 takes precedence).}

{in circuits having distributed constants.}
Arrangements for measuring time integral of electric power or current, e.g. by electricity meters (electromechanical arrangements therefor G01R 11/00; monitoring electric consumption of electrically-propelled vehicles H60L 3/00; coin freed devices G07F 15/00)

NOTE
An arrangement for measuring time integral of electric power is classified in group G01R 21/00 if the essential characteristic is the measuring of electric power.

by electrolytic methods
by calorimetric methods
by electronic methods
[Details of electronic electricity meters]
related to remote communication
related to mechanical aspects
[Arrangements for avoiding or indicating fraudulent use]
[Arrangements for indicating or signaling faults]
using analogue techniques
using digital techniques

Arrangements for measuring frequencies;
Arrangements for analysing frequency spectra (frequency discriminators H03D; [high frequency probes G01R 1/06772])

[Circuits for comparing several input signals and for indicating the result of this comparison, e.g. equal, different, greater, smaller (comparing phase or frequency of 2 mutually independent oscillations in demodulators)]

Arrangements for measuring frequency, e.g. pulse repetition rate ([using vibrating reeds G01R 9/04])
Arrangements for measuring period of current or voltage (measuring short-time intervals G04F)
adapted for measuring in circuits having distributed constants
by converting frequency into an amplitude of current or voltage
using response of circuits tuned on resonance, e.g. grid-drip meter
using response of circuits tuned off resonance

using analogue integrators, e.g. capacitors establishing a mean value by balance of input signals and defined discharge signals or leakage (radiation-measuring instruments in which pulses generated by a radiation detector are integrated G01T 1/15)

by converting frequency into a train of pulses, which are then counted [, i.e. converting the signal into a square wave]

by heterodyning; by beat-frequency comparison (generation of oscillations by beating unmodulated signals of different frequencies H03B 21/00)

by heterodyning or by beat-frequency comparison with the harmonic of an oscillator

Indicating that frequency of pulses is either above or below a predetermined value or within or outside a predetermined range of values, by making use of non-linear or digital elements (indicating that pulse width is above or below a certain limit)

[giving an indication of the number of times this occurs, i.e. multi-channel analysers (for pulse characteristics)]

Spectrum analysis; Fourier analysis ([computing with Fourier series or Walsh functions G06F 17/14, G06F 7/19; spectral data processing])

adapted for measuring in circuits having distributed constants
using filters
with digital filters
with optical [or acoustical] auxiliary devices
Wobbulating devices similar to swept panoramic receivers (panoramic receivers per se H03J 7/32)
by delay means, e.g. tapped delay lines
Analysis of very low frequencies
with provision for recording frequency spectrum
Measurement of non-linear distortion [, e.g. harmonics or noise (G01R 31/3708 takes precedence; noise figure G01R 29/26)]

Arrangements for measuring phase angle between a voltage and a current, or between voltages or currents (measuring power factor G01R 21/00; measuring position of individual pulses in a pulse train G01R 29/02; phase discriminators H03D)

[Circuits for comparing several input signals and for indicating the result of this comparison, e.g. equal, different, greater, smaller, or for passing one of the input signals as output signal]
in circuits having distributed constants
involving adjustment of a phase shifter to produce a predetermined phase difference, e.g. zero difference
employing quotient instrument
by counting of standard pulses (measuring time intervals G04F)

Arrangements for measuring resistance, reactance, impedance, or electric characteristics derived therefrom (measuring superconductive properties G01R 33/1238)
NOTE
Groups G01R 27/02 - G01R 27/22 cover variables that directly or indirectly can be measured over two poles of a component or a Thévenin two-pole equivalent. Subgroup G01R 27/26 also covers other techniques, e.g. using electromagnetic waves or network analyzers.

27/025  ... [Measuring very high resistances, e.g. isolation resistances, i.e. megohm-meters]

27/04  ... in circuits having distributed constants [., e.g. having very long conductors or involving high frequencies]

27/06  ... Measuring reflection coefficients; Measuring standing-wave ratio

27/08  ... Measuring resistance by measuring both voltage and current

27/10  ... using two-coil or crossed-coil instruments forming quotient

27/12  ... using hand generators, e.g. meggers

27/14  ... Measuring resistance by measuring current or voltage obtained from a reference source (G01R 27/16, G01R 27/20, G01R 27/22 take precedence)

27/16  ... Measuring impedance of element or network through which a current is passing from another source, e.g. cable, power line

27/18  ... Measuring resistance to earth [., i.e. line to ground]

27/20  ... Measuring earth resistance; Measuring contact resistance, [., e.g.] of earth connections, e.g. plates

27/205  ... [Measuring contact resistance of connections, e.g. of earth connections]

27/22  ... Measuring resistance of fluids (measuring vessels, electrodes therefor G01N 27/07)

27/26  ... Measuring inductance or capacitance; Measuring quality factor, e.g. by using the resonance method; Measuring loss factor; Measuring dielectric constants [., Measuring impedance or related variables]

27/2605  ... [Measuring capacitance (capacitive sensors G01D 5/24)]

27/2611  ... [Measuring inductance]

27/2617  ... [Measuring dielectric properties, e.g. constants (testing dielectric strength G01R 31/12; detecting insulation faults G01R 31/52; G01R 27/2688 takes precedence)]

27/2623  ... [Measuring-systems or electronic circuits (G01R 27/2635, G01R 27/2682 take precedence)]

27/2629  ... [Bridge circuits (bridges for measuring loss angle G01R 27/2694)]

27/2635  ... [Sample holders, electrodes or excitation arrangements, e.g. sensors or measuring cells]

27/2641  ... [of plate type, i.e. with the sample sandwiched in the middle]

27/2647  ... [of coaxial or concentric type, e.g. with the sample in a coaxial line]
29/0814 . . . [Field measurements related to measuring influence on or from apparatus, components or humans (EMC, EMI and similar testing in general G01R 31/01), c.g. in ESD, EMI, EMC, EMP testing, measuring radiation leakage; detecting presence of micro- or radiowave emitters; dosimetry; testing shielding; measurements related to lightning]

29/0821 . . . [rooms and test sites therefor, e.g. anechoic chambers, open field sites or TEM cells (for testing antennas G01R 29/105)]

29/0828 . . . [TEM-cells]

29/0835 . . . [Testing shielding, e.g. for efficiency]

29/0842 . . . [Measurements related to lightning, e.g. measuring electric disturbances, warning systems]

29/085 . . . [for detecting presence or location of electric lines or cables (fault detection G01R 31/50; fault location G01R 31/08)]

29/0857 . . . [Dosimetry, i.e. measuring the time integral of radiation intensity; Level warning devices for personal safety use (nuclear radiation dosimetry G01T)]

29/0864 . . . [characterised by constructional or functional features]

29/0871 . . . [Complete apparatus or systems; circuits, e.g. receivers or amplifiers (G01R 29/0878; G01R 29/0892 take precedence; dosimeters, warning devices G01R 29/0857)]

29/0878 . . . [Sensors; antennas; probes; detectors (wave guide measuring sections G01R 1/24)]

29/0885 . . . [using optical probes, e.g. electro-optical, luminiscent, glow discharge, or optical interferometers]

29/0892 . . . [Details related to signal analysis or treatment; presenting results, e.g. displays; measuring specific signal features other than field strength, e.g. polarisation, field modes, phase, envelope, maximum value]

29/10 . . . Radiation diagrams of antennas

29/105 . . . [using anechoic chambers; Chambers or open field sites used therefor (test sites used for measuring on other objects than aerials G01R 29/0828; wave absorbing devices H01Q 17/00)]

29/12 . . . Measuring electrostatic fields [or voltage-potential]

29/14 . . . Measuring field distribution

29/16 . . . Measuring asymmetry of polyphase networks

29/18 . . . Indicating phase sequence; Indicating synchronism

29/20 . . . Measuring number of turns; Measuring transformation ratio or coupling factor of windings ([testing or calibrating instrument transformers G01R 35/02])

29/22 . . . Measuring piezo-electric properties

29/24 . . . [Arrangements for measuring quantities of charge (electrostatic instruments G01R 5/28; indicating presence of current G01R 19/15; electrolytic meters, calorimetric meters, for measuring time integral of electric current G01R 22/02, G01R 22/04)]

29/26 . . . Measuring noise figure; Measuring signal-to-noise ratio [Measuring jitter, i.e. phase noise, (distortion G01R 23/20; noise measuring in individual transistors G01R 31/2016, G01R 31/2026)]

31/00 Arrangements for testing electric properties; Arrangements for locating electric faults; Arrangements for electrical testing characterised by what is being tested not provided for elsewhere [measuring superconductive properties G01R 33/1238; testing or measuring semiconductors or solid state devices during manufacture (H01L 22/00); testing line transmission systems H04B 3/46]

NOTE

Groups G01R 31/08, G01R 31/12, G01R 31/327, G01R 31/24, G01R 31/26, G01R 31/34, G01R 31/36, G01R 31/40, G01R 31/44 take precedence over group G01R 31/50.

31/001 . . . [Measuring interference from external sources to, or emission from, the device under test, e.g. EMC, EMI, EMP or ESD testing (measuring electromagnetical fields G01R 29/08; circuits for generating HV pulses in dielectric strength testing G01R 31/14)]

31/002 . . . [where the device under test is an electronic circuit]

31/003 . . . [Environmental or reliability tests (of individual semiconductors G01R 31/2642; of PCB's G01R 31/2817; of IC's G01R 31/2855; of other circuits G01R 31/2849)]

31/005 . . . [Testing of electric installations on transport means]

31/006 . . . [on road vehicles, e.g. automobiles or trucks (testing of ignition installations peculiar to internal combustion engines F02P 17/00)]

31/007 . . . [using microprocessors or computers]

31/008 . . . [on air- or spacecraft, railway rolling stock or sea-going vessels]

31/01 . . . Subjecting similar articles in turn to test, e.g. "go/no-go" tests in mass production; Testing objects at points as they pass through a testing station (testing of cables continuously passing the testing apparatus G01R 31/59; testing dielectric strength or breakdown voltage G01R 31/12)

WARNING

Group G01R 31/01 is impacted by reclassification into groups G01R 31/12 and G01R 31/59. Groups G01R 31/01, G01R 31/12 and G01R 31/59 should be considered in order to perform a complete search.

31/013 . . . [Testing passive components (testing relays G01R 31/3278; testing electrical windings, e.g. inductors G01R 31/72)]

31/016 . . . [Testing of capacitors (measuring capacitance G01R 27/2605)]

31/08 . . . Locating faults in cables, transmission lines, or networks

31/081 . . . [according to type of conductors]

31/083 . . . [in cables, e.g. underground]

31/085 . . . [in power transmission or distribution lines, e.g. overhead]

31/086 . . . [in power transmission or distribution networks, i.e. with interconnected conductors]

31/088 . . . [Aspects of digital computing]
31/10 by increasing destruction at fault, e.g. burning-in by using a pulse generator operating a special programme
31/11 using pulse reflection methods
31/12 Testing dielectric strength or breakdown voltage ; testing of monitoring or effectiveness or level of insulation, e.g. of a cable or of an apparatus, for example using partial discharge measurements; Electrostatic testing (G01R 31/06, G01R 31/27 and G01R 31/72 take precedence; measuring in plasmas G01R 19/0061; measuring dielectric constants G01R 27/2617; ESD, EMC or EMP testing of circuits G01R 31/002)

**WARNING**

Group G01R 31/12 is incomplete pending reclassification of documents from group G01R 31/01.
Groups G01R 31/01 and G01R 31/12 should be considered in order to perform a complete search.

31/1209 [using acoustic measurements (acoustic measurements G01H 3/00)]
31/1218 [using optical methods; using charged particle, e.g. electron, beams or X-rays]
31/1227 [of components, parts or materials (G01R 31/1209, G01R 31/1218, G01R 31/18 take precedence; circuits therefor G01R 31/14; testing vessels of electrodes G01R 31/16)]
31/1236 [of surge arresters (monitoring overvoltage diverters or arresters H02H 3/0481)]
31/1245 [of line insulators or spacers, e.g. ceramic overhead line cap insulators; of insulators in HV bushings]
31/1254 [of gas-insulated power appliances or vacuum gaps (testing switches G01R 31/327; detecting electrical or mechanical defects in encased switchgear H02B 13/065)]
31/1263 [of solid or fluid materials, e.g. insulation films, bulk material; of semiconductors or LV electronic components or parts; of cable, line or wire insulation]
31/1272 [of cable, line or wire insulation, e.g. using partial discharge measurements (locating faults in cables G01R 31/083)]
31/1281 [of liquids or gases]
31/129 [of components or parts made of semiconducting materials; of LV components or parts (G01R 31/18 takes precedence)]
31/14 Circuits therefor (e.g. for generating test voltages, sensing circuits (G01R 31/1209 - G01R 31/1227 take precedence; for testing switches G01R 31/327))
31/16 Construction of testing vessels; Electrodes therefor
31/18 Subjecting similar articles in turn to test, e.g. go/no-go tests in mass production
31/20 Preparation of articles or specimens to facilitate testing
31/24 Testing of discharge tubes (during manufacture H01J 9/42)
31/245 [Testing of gas discharge tubes]
31/25 Testing of vacuum tubes
31/252 [Testing of electron multipliers, e.g. photomultipliers]
31/255 [Testing of transit-time tubes, e.g. klystrons, magnetrons]
31/257 [Testing of beam-tubes, e.g. cathode-ray tubes, image pick-up tubes (of channel image intensifier arrays G01R 31/252; of transit time tubes G01R 31/255)]
31/26 Testing of individual semiconductor devices (testing or measuring during manufacture or treatment (H04L 22/00); testing of photovoltaic devices H02S 5/01)
31/2601 [Apparatus or methods therefor (G01R 31/2607, G01R 31/2642 take precedence)]
31/2603 [for curve tracing of semiconductor characteristics, e.g. on oscilloscope]
31/2607 [Circuits therefor (G01R 31/2642 takes precedence)]
31/2608 [for testing bipolar transistors]
31/261 [for measuring break-down voltage or punch through voltage therefor]
31/2612 [for measuring frequency response characteristics, e.g. cut-off frequency thereof]
31/2614 [for measuring gain factor thereof]
31/2616 [for measuring noise (measuring noise factor in general G01R 29/26)]
31/2617 [for measuring switching properties thereof]
31/2619 [for measuring thermal properties thereof]
31/2621 [for testing field effect transistors, i.e. FET’s]
31/2623 [for measuring break-down voltage thereof]
31/2625 [for measuring gain factor thereof]
31/2626 [for measuring noise (measuring noise factor in general G01R 29/26)]
31/2628 [for measuring thermal properties thereof]
31/263 [for testing thyristors]
31/2632 [for testing diodes]
31/2633 [for measuring switching properties thereof]
31/2635 [for curve tracing of semiconductor characteristics, e.g. on oscilloscope]
31/2637 [for measuring gain factor thereof]
31/2638 [for measuring noise (measuring noise factor in general G01R 29/26)]
31/2639 [for measuring switching properties thereof]
31/2641 [for testing charge coupled devices]
31/2642 [Testing semiconductor operation lifetime or reliability, e.g. by accelerated life tests]
31/2644 [Adaptations of individual semiconductor devices to facilitate the testing thereof]
31/2646 [for measuring noise (G01R 31/2616, G01R 31/2626 take precedence)]
31/2648 [Characterising semiconductor materials (testing of materials or semi-finished products G01R 31/2831; testing during manufacture H01L 22/00)]
31/265 [Contactless testing (of circuits, also in wafer-form G01R 31/302)]
31/2653 [using electron beams]
31/2656 [using non-ionising electromagnetic radiation, e.g. optical radiation]
31/27 . . . Testing of devices without physical removal from the circuit of which they form part, e.g. compensating for effects surrounding elements (testing printed circuit boards G01R 31/2801)

31/275 . . . (for testing individual semiconductor components within integrated circuits)

31/28 . . . Testing of electronic circuits, e.g. by signal tracer (EMC, EMP or similar testing of electronic circuits G01R 31/002); testing for short-circuits, discontinuities, leakage or incorrect line connection G01R 31/50; checking computers (or computer components) G01F 11/00; checking static stores for correct operation G11C 29/00; [testing receivers or transmitters of transmission systems H04B 17/00])

31/2801 . . . (Testing of printed circuits, backplanes, motherboards, hybrid circuits or carriers for multichip packages (MCP) G01R 31/318508 takes precedence; contactless testing G01R 31/302; testing contacts or connections G01R 31/66)

31/2803 . . . (by means of functional tests, e.g. logic-circuit-simulation or algorithms therefor (testing electronic digital computers G06F 11/00))

31/2805 . . . (bare printed circuit boards)

31/2806 . . . (Apparatus therefor, e.g. test stations, drivers, analysers, conveyors G01R 31/2805, G01R 31/281, G01R 31/2818 take precedence)

31/2808 . . . (Holding, conveying or contacting devices, e.g. test adapters, edge connectors, extender boards (probe, multiprobe, probe manipulator or probe fixture G01R 1/067))

31/281 . . . (Specific types of tests or tests for a specific type of fault, e.g. thermal mapping, shorts testing G01R 31/2818 takes precedence)

31/2812 . . . (Checking for open circuits or shorts, e.g. solder bridges; Testing conductivity, resistivity or impedance (of connections G01R 31/66))

31/2813 . . . (Checking the presence, location, orientation or value, e.g. resistance, of components or conductors (orientation of the DUT with respect to the test fixture G01R 1/06755, G01R 31/281))

31/2815 . . . (Functional tests, e.g. boundary scans, using the normal I/O contacts (contacting devices G01R 31/2808; testing digital circuits G01R 31/281, G06F 11/00))

31/2817 . . . (Environmental-, stress-, or burn-in tests (of IC's G01R 31/2855; of individual semiconductors G01R 31/2642; of other circuits G01R 31/2849))

31/2818 . . . (using test structures on, or modifications of, the card under test, made for the purpose of testing, e.g. additional components or connectors G01R 31/2805 takes precedence; printed circuits having, e.g. symbols, test patterns or visualisation means H05K 1/0266)

31/282 . . . (Testing of electronic circuits specially adapted for particular applications not provided for elsewhere (G01R 31/2801 and G01R 31/2851 take precedence))

NOTE
References listed below indicate CPC places which could also be of interest when carrying out a search in respect of the subject matter covered by the preceding group:
- testing of individual LEDs G01R 31/2635
- testing of lamps G01R 31/44
- testing of displays and display drivers, e.g. LCDs G09G 3/006
- testing of ADCs or DACs H03M 1/1071

31/2822 . . . (of microwave or radiofrequency circuits (of attenuation, gain, e.g. using network analyzers G01R 27/28))

31/2824 . . . (testing of oscillators or resonators)

31/2825 . . . ([in household appliances or professional audio/video equipment (testing LAN's H04L 43/50; testing TV systems H04N 17/00; testing loudspeakers H04R 29/00))

31/2827 . . . (Testing of electronic protection circuits (testing switches G01R 31/327; checking alarm systems G08B 29/00; self test of summation current transformers H02H 3/335))

31/2829 . . . (Testing of circuits in sensor or actuator systems (testing of apparatus for measuring electric or magnetic variables G01R 35/00; testing of indicating or recording apparatus G01D; in airbag systems B60R 21/017; checking gas analysers G01N 33/007; monitoring or fail-safe circuits for electromagnets H01F 7/1844))

31/2831 . . . (Testing of materials or semi-finished products, e.g. semiconductor wafers or substrates (G01R 31/318511 takes precedence; testing during manufacture H01L 22/00))

31/2832 . . . (Specific tests of electronic circuits not provided for elsewhere (G01R 31/2801, G01R 31/316 take precedence))

31/2834 . . . (Automated test systems [ATE]; using microprocessors or computers (G01R 31/317 takes precedence; ATE for detection of defective computer hardware G06F 11/2736))

31/2836 . . . (Fault-finding or characterising (G01R 31/2822 - G01R 31/2831 take precedence))

31/2837 . . . (Characterising or performance testing, e.g. of frequency response (transient response G01R 27/28))

31/2839 . . . (using signal generators, power supplies or circuit analysers (G01R 31/2879 takes precedence; multimeters G01R 15/12, network analysers G01R 27/28))

31/2841 . . . . . . (Signal generators)

31/2843 . . . . . . (In-circuit-testing)

31/2844 . . . . . . (using test interfaces, e.g. adapters, test boxes, switches, PIN drivers (G01R 31/2889 takes precedence))

31/2846 . . . . . . (using hard- or software simulation or using knowledge-based systems, e.g. expert systems, artificial intelligence or interactive algorithms)

31/2848 . . . . . . (using simulation)

31/2849 . . . . . . (Environmental or reliability testing, e.g. burn-in or validation tests (of individual semiconductors G01R 31/2642; of printed circuit boards G01R 31/2817; of IC's G01R 31/2855))
Testing of integrated circuits [IC] (G01R 31/317 takes precedence; testing individual devices G01R 31/26; testing printed circuits G01R 31/2801)

[Electrical testing of internal connections or -isolation, e.g. latch-up or chip-to-lead connections (G01R 31/31717 takes precedence; test of chip-to-PCB or lead-to-PCB connections G01R 31/66)]

[Environmental, reliability or burn-in testing]

[Internal circuit aspects, e.g. built-in test features; Test chips; Measuring material aspects, e.g. electro migration [EM]]

[Measuring of material aspects, e.g. electro-migration [EM], hot carrier injection]

[External aspects, e.g. related to chambers, contacting devices or handlers]

[Chambers or ovens; Tanks]

[Contacting devices, e.g. sockets, burn-in boards or mounting fixtures (in general G01R 1/06)]

[Holding devices, e.g. chucks; Handlers or transport devices (having contacts G01R 31/2863)]

[Handlers or transport devices, e.g. loaders, carriers, trays]

[Complete testing stations; systems; procedures; software aspects]

[Procedures; Software aspects]

[related to electrical or environmental aspects, e.g. temperature, humidity, vibration, nuclear radiation]

[related to temperature]

[related to heating]

[related to cooling]

[related to electrical aspects, e.g. to voltage or current supply or stimuli or to electrical loads]

[related to environmental aspects other than temperature, e.g. humidity or vibrations]

[Testing timing characteristics]

[using dedicated test connectors, test elements or test circuits on the IC under test (G01R 31/2855 takes precedence)]

[Features relating to contacting the IC under test, e.g. probe heads; chucks (G01R 31/2865 takes precedence, test connections, e.g. test sockets, or probes per se, G01R 1/04 or G01R 1/06)]

[involving moving the probe head or the IC under test; docking stations (moving single probes G01R 1/06705; moving individual probes in multiple probes G01R 1/07392)]

[Interfaces, e.g. between probe and tester (G01R 31/31905 and G01R 1/07364 take precedence)]

[related to sensing or controlling of force, position, temperature (G01R 31/2874 takes precedence; sensing of force G01L; sensing of position G01B, G01D; sensing of temperature G01K; controlling in general G05)]

[Handling, conveying or loading, e.g. belts, boats, vacuum fingers (G01R 31/2867 takes precedence; handling semiconductor devices or wafers during manufacture or treatment H01L 21/67)]

[Aspects of quality control [QC] (G01R 31/31718 takes precedence; program control for QC G05B 19/41875)]

[Testing of IC packages; Test features related to IC packages (containers per se H01L 23/02, encapsulations per se H01L 23/26)]

[Sample preparation, e.g. removing encapsulation, etching (sample preparation in general G01N 1/00)]

[Marginal testing, e.g. by varying supply voltage (testing computers during standby operation or idle time G06F 11/22)]

[Current or voltage test]

[Quiescent current [IDDQ] test or leakage current test]

[Built-In-Current test [BIC]]

[Delay or race condition test, e.g. race hazard test]

[Contactless testing (G01R 31/66 takes precedence)]

[Wireless interface with the DUT]

[of integrated circuits (G01R 31/305, G01R 31/315 take precedence)]

[of printed or hybrid circuits (G01R 31/305, G01R 31/315 take precedence)]

[using electron beams (investigating or analysing materials by measuring photoelectric effect G01N 21/00; image analysis G06T 7/00)]

[printed or hybrid circuits]

[of printed or hybrid circuits]

[of integrated circuits]

[using non-ionising electromagnetic radiation, e.g. optical radiation ([investigating or analysing materials by using of optical means G01N 21/00; image analysis G06T 7/00])]

[of printed or hybrid circuits [or circuit substrates]]

[of integrated circuits (G01R 31/31728 takes precedence)]

[by capacitive methods]

[by inductive methods]

[Testing of analog circuits (G01R 31/2851 takes precedence)]

[Marginal testing]

[Functional testing]

[Testing of combined analog and digital circuits ([testing ADC's H03M 1/1071])]
31/31702 ... {Testing digital circuits including elements other than semiconductor transistors, e.g. biochips, nanofabrics, mems, chips with magnetic elements}
31/31703 ... {Comparison aspects, e.g. signature analysis, comparators (concerning scan tests G01R 31/318566; concerning testers G01R 31/3193)}
31/31704 ... {Design for test; Design verification (concerning scan tests G01R 31/318583; computer-aided design G00F 30/00)}
31/31705 ... {Debugging aspects, e.g. using test circuits for debugging, using dedicated debugging test circuits (generation of test sequences therefor G01R 31/31835, using scan test therefor G01R 31/318544)}
31/31706 ... {involving differential digital signals, e.g. testing differential signal circuits, using differential signals for testing}
31/31707 ... {Test strategies (methods for generation of test sequences G01R 31/318371)}
31/31708 ... {Analysis of signal quality (G01R 31/31901 takes precedence; measuring frequencies or analysing frequency spectra per se G01R 23/00; measuring non-linear distortion per se G01R 23/20)}
31/31709 ... {Jitter measurements; Jitter generators (measuring jitter, noise figure or signal-to-noise ratio per se G01R 29/26; analysis of tester signals G01R 31/31901)}
31/3171 ... {BER [Bit Error Rate] test}
31/31711 ... {Evaluation methods, e.g. shmoo plots}
31/31712 ... {Input or output aspects}
31/31713 ... {Input or output interfaces for test, e.g. test pins, buffers (for scan test G01R 31/318722)}
31/31715 ... {Testing of input or output circuits; test of circuitry between the IC pins and the functional core, e.g. testing of input or output driver, receiver, buffer}
31/31716 ... {Testing of input or output with loop-back}
31/31717 ... {Interconnect testing (by scan techniques see G01R 31/31855)}
31/31718 ... {Logistic aspects, e.g. binning, selection, sorting of devices under test, tester/handler interaction networks, Test management software, e.g. software for test statistics or test evaluation, yield analysis (mechanical aspects G01R 31/2808, G01R 31/2851)}
31/31719 ... {Security aspects, e.g. preventing unauthorised access during test}
31/3172 ... {Optimisation aspects, e.g. using functional pin as test pin, pin multiplexing}
31/31721 ... {Power aspects, e.g. power supplies for test circuits, power saving during test (for scan test G01R 31/318575)}
31/31722 ... {Addressing or selecting of test units, e.g. transmission protocols for selecting test units (for scan test G01R 31/318558)}
31/31723 ... {Hardware for routing the test signal within the device under test to the circuits to be tested, e.g. multiplexer for multiple core testing, accessing internal nodes (routing the test signal to or from the device under test G01R 31/31926)}
31/31724 ... {Test controller, e.g. BIST state machine (for scan test G01R 31/318555)}
31/31725 ... {Timing aspects, e.g. clock distribution, skew, propagation delay (for tester hardware G01R 31/31937)}
31/31726 ... {Synchronization, e.g. of test, clock or strobe signals; Signals in different clock domains; Generation of Vernier signals; Comparison and adjustment of the signals}
31/31727 ... {Clock circuits aspects, e.g. test clock circuit details, timing aspects for signal generation, circuits for testing clocks (G01R 31/31725 takes precedence; concerning scan test G01R 31/318552; for tester hardware G01R 31/31922)}
31/31728 ... {Optical aspects, e.g. opto-electronics used for testing, optical signal transmission for testing electronic circuits, electro-optic components to be tested in combination with electronic circuits, measuring light emission of digital circuits (probes having electro-optic elements G01R 1/071; electro-optic sampling for oscilloscopes G01R 13/347; contactless testing of individual semiconductor devices by optical means G01R 31/2656)}
31/3173 ... {Marginal testing}
31/3177 ... {Testing of logic operation, e.g. by logic analysers}
31/3181 ... {Functional testing (G01R 31/3177 takes precedence)}
31/31813 ... {Test pattern generators}
31/31816 ... {Soft error testing; Soft error rate evaluation; Single event testing}
31/3183 ... {Generation of test inputs, e.g. test vectors, patterns or sequences}
31/318307 ... {computer-aided, e.g. automatic test program generator [ATPG], program translations, test program debugging}
31/318314 ... {Tools, e.g. program interfaces, test suite, test bench, simulation hardware, test compiler, test program languages (simulation software G01R 31/318357; emulators G06F 11/261)}
31/318321 ... {for combinational circuits}
31/318328 ... {for delay tests}
31/318335 ... {Test pattern compression or decompression (compression or decompression of scan patterns G01R 31/318547; compression or decompression hardware G01R 31/31921)}
31/318342 ... {by preliminary fault modelling, e.g. analysis, simulation}
31/31835 ... {Analysis of test coverage or failure detectability}
31/318357 ... {Simulation (computer simulation of digital circuits G06F 30/3308)}
31/318364 ... {as a result of hardware simulation, e.g. in an HDL environment (computer-aided simulation of circuits G06F 30/3308)}
31/318371 ... {Methodologies therefor, e.g. algorithms, procedures}
31/318378 ... {of patterns for devices arranged in a network}
31/318385 ... {Random or pseudo-random test pattern}
31/318392 . . . . . . . . {for sequential circuits (G01R 31/318544 takes precedence)}
31/3185 . . . . . . . . Reconfiguring for testing, e.g. LSSD, partitioning
31/318502 . . . . . . . . {Test of Combinational circuits}
31/318505 . . . . . . . . {Test of Modular systems, e.g. Wafers, MCM's}
31/318508 . . . . . . . . {Board Level Test, e.g. P1500 Standard (features related to boundary scan G01R 31/318533)}
31/318511 . . . . . . . . {Wafer Test}
31/318513 . . . . . . . . {Test of Multi-Chip-Modules}
31/318516 . . . . . . . . {Test of programmable logic devices [PLDs]}
31/318519 . . . . . . . . {Test of field programmable gate arrays [FPGA]}
31/318522 . . . . . . . . {Test of Sequential circuits (test of microprocessors G06F 11/2236, test of ALU's G06F 11/2276)}
31/318525 . . . . . . . . {Test of flip-flops or latches}
31/318527 . . . . . . . . {Test of counters}
31/31853 . . . . . . . . {Test of registers}
31/318533 . . . . . . . . {using scanning techniques, e.g. LSSD, Boundary Scan, JTAG}
31/318536 . . . . . . . . {Scan chain arrangements, e.g. connections, test bus, analog signals}
31/318538 . . . . . . . . {Topological or mechanical aspects}
31/318541 . . . . . . . . {Scan latches or cell details}
31/318544 . . . . . . . . {Scanning methods, algorithms and patterns (G01R 31/3183 takes precedence)}
31/318547 . . . . . . . . {Data generators or compressors}
31/31855 . . . . . . . . {Interconnection testing, e.g. crosstalk, shortcircuits}
31/318552 . . . . . . . . {Clock circuits details}
31/318555 . . . . . . . . {Control logic}
31/318558 . . . . . . . . {Addressing or selecting of subparts of the device under test}
31/318561 . . . . . . . . {Identification of the subpart}
31/318563 . . . . . . . . {Multiple simultaneous testing of subparts}
31/318566 . . . . . . . . {Comparators; Diagnosing the device under test}
31/318569 . . . . . . . . {Error indication, logging circuits}
31/318572 . . . . . . . . {Input/Output interfaces}
31/318575 . . . . . . . . {Power distribution; Power saving}
31/318577 . . . . . . . . {AC testing, e.g. current testing, burn-in}
31/31858 . . . . . . . . {Delay testing}
31/318583 . . . . . . . . {Design for test}
31/318586 . . . . . . . . {with partial scan or non-scannable parts}
31/318588 . . . . . . . . {Security aspects}
31/318591 . . . . . . . . {Tools}
31/318594 . . . . . . . . {Timing aspects (clock circuits G01R 31/318552)}
31/318597 . . . . . . . . {JTAG or boundary scan test of memory devices (other scan testing of memories G11C 29/232)}
31/3187 . . . . . . . . Built-in tests
31/319 . . . . . . . . Tester hardware, i.e. output processing circuit {logic analyzers G01R 31/3177; Memory tester hardware G11C 29/56}
31/31901 . . . . . . . . {Analysis of tester Performance; Tester characterization}
31/31903 . . . . . . . . {tester configuration}
31/31905 . . . . . . . . {Interface with the device under test [DUT], e.g. arrangements between the test head and the DUT, mechanical aspects, fixture}
31/31907 . . . . . . . . {Modular tester, e.g. controlling and coordinating instruments in a bus based architecture}
31/31908 . . . . . . . . {Tester set-up, e.g. configuring the tester to the device under test [DUT], down loading test patterns}
31/3191 . . . . . . . . {Calibration}
31/31912 . . . . . . . . {Tester/user interface}
31/31914 . . . . . . . . {Portable Testers}
31/31915 . . . . . . . . {In-circuit Testers}
31/31917 . . . . . . . . {Stimuli generation or application of test patterns to the device under test [DUT]}
31/31919 . . . . . . . . . {using compression techniques, e.g. patterns sequencer}
31/31922 . . . . . . . . . {Timing generation or clock distribution (G01R 31/3191 takes precedence)}
31/31924 . . . . . . . . . {Voltage or current aspects, e.g. driver, receiver}
31/31926 . . . . . . . . . {Routing signals to or from the device under test [DUT], e.g. switch matrix, pin multiplexing}
31/31928 . . . . . . . . . {Formatter (driver, receiver details G01R 31/3124)}
31/3193 . . . . . . . . {with comparison between actual response and known fault free response (receiver details G01R 31/31924)}
31/31932 . . . . . . . . {Comparators}
31/31935 . . . . . . . . {Storing data, e.g. failure memory}
31/31937 . . . . . . . . {Timing aspects, e.g. measuring propagation delay (G01R 31/3191 and G01R 31/3192 take precedence; marginal testing G06F 11/224)}
31/327 . . . . . . . . Testing of circuit interrupters, switches or circuit-breakers
31/3271 . . . . . . . . {of high voltage or medium voltage devices (G01R 31/33 takes precedence)}
31/3272 . . . . . . . . {Apparatus, systems or circuits therefor (G01R 31/3275 takes precedence)}
31/3274 . . . . . . . . {Details related to measuring, e.g. sensing, displaying or computing; Measuring of variables related to the contact pieces, e.g. wear, position or resistance (measuring contact resistance G01R 27/205)}
31/3275 . . . . . . . . {Fault detection or status indication}
31/3277 . . . . . . . . {of low voltage devices, e.g. domestic or industrial devices, such as motor protections, relays, rotation switches}
31/3278 . . . . . . . . {of relays, solenoids or reed switches (measuring contact resistance G01R 27/205; high voltage magnetic switches G01R 31/3271, G01R 31/33; testing electric windings G01R 31/72; monitoring of fail safe circuits H01H 47/002)}
Testing of the switching capacity of high-voltage circuit-breakers [: Testing of breaking capacity or related variables, e.g. post arc current or transient recovery voltage] 31/333 . . . [Apparatus, systems or circuits therefor] 31/3336 . . . . [Synthetic testing, i.e. with separate current and voltage generators simulating distance fault conditions]

Testing dynamo-electric machines 31/34 . . . [in operation] 31/346 . . . [Testing of armature or field windings] 31/36 . Arrangements for testing, measuring or monitoring the electrical condition of accumulators or electric batteries, e.g. capacity or state of charge [SoC]

NOTE

[This group covers arrangements for measuring, testing or indicating electrical conditions or variables of accumulators or electric batteries. Arrangements for monitoring, measuring, testing or indicating condition structurally associated with the battery are covered by H01M, e.g. by group H01M 10/48]

Battery terminal connectors with integrated measuring arrangements 31/3644 . . . [Constructional arrangements] 31/3646 . . . [for indicating electrical conditions or variables, e.g. visual or audible indicators] 31/3647 . . . [for determining the ability of a battery to perform a critical function, e.g. cranking] 31/3648 . . . [comprising digital calculation means, e.g. for performing an algorithm] 31/367 . . . Software therefor, e.g. for battery testing using modelling or look-up tables 31/371 . . . with remote indication, e.g. on external chargers 31/374 . . . with means for correcting the measurement for temperature or ageing 31/378 . . . specially adapted for the type of battery or accumulator

for lead-acid batteries 31/379 . . . . [Primary cells, i.e. not rechargeable] 31/382 . . . Arrangements for monitoring battery or accumulator variables, e.g. SoC 31/3828 . . . using current integration 31/3832 . . . without measurement of battery voltage 31/3833 . . . . [using analog integrators, e.g. coulomb-meters] 31/3835 . . . involving only voltage measurements 31/3842 . . . combining voltage and current measurements 31/385 . . . Arrangements for measuring battery or accumulator variables (for monitoring G01R 31/382)

using test-loads] 31/3865 . . . [related to manufacture, e.g. testing after manufacture] 31/387 . . . Determining ampere-hour charge capacity or SoC 31/388 . . . involving voltage measurements 31/389 . . . Measuring internal impedance, internal conductance or related variables 31/392 . . . Determining battery ageing or deterioration, e.g. state of health

Acquisition or processing of data for testing or for monitoring individual cells or groups of cells within a battery 31/396 . . . . Testing power supplies (testing photovoltaic devices H02S 50/10)

Testing of electric apparatus, lines, cables or components for short-circuits, continuity, leakage current or incorrect line connections (testing of sparking plugs H01T 13/58)

WARNING

Group G01R 31/50 is impacted by reclassification into groups G01R 31/52, G01R 31/54, G01R 31/55 and G01R 31/56. Groups G01R 31/50, G01R 31/52, G01R 31/54, G01R 31/55 and G01R 31/56 should be considered in order to perform a complete search.

Testing for short-circuits, leakage current or ground faults 31/52 . . . . Testing for continuity

WARNING

Group G01R 31/52 is incomplete pending reclassification of documents from group G01R 31/50. Groups G01R 31/50 and G01R 31/52 should be considered in order to perform a complete search.

Testing for incorrect line connections 31/55 . . . . Testing of electric apparatus (testing of transformers G01R 31/62; testing of connections G01R 31/66)

WARNING

Group G01R 31/55 is incomplete pending reclassification of documents from group G01R 31/50. Groups G01R 31/50 and G01R 31/55 should be considered in order to perform a complete search.

Testing of lines, cables or conductors (testing of electric windings G01R 31/72) 31/58 . . .
31/59 . . . while the cable continuously passes the testing apparatus, e.g. during manufacture

**WARNING**

Group G01R 31/59 is incomplete pending reclassification of documents from group G01R 31/01.

Groups G01R 31/01 and G01R 31/59 should be considered in order to perform a complete search.

31/60 . . . Identification of wires in a multicore cable

31/62 . . . Testing of transformers

**WARNING**

Group G01R 31/62 is incomplete pending reclassification of documents from group G01R 31/72.

Groups G01R 31/72 and G01R 31/62 should be considered in order to perform a complete search.

31/64 . . . Testing of capacitors

31/66 . . . Testing of connections, e.g. of plugs or non-disconnectable joints (testing for incorrect line connections G01R 31/55)

31/67 . . . Testing the correctness of wire connections in electric apparatus or circuits

31/68 . . . Testing of releasable connections, e.g. of terminals mounted on a printed circuit board

31/69 . . . . . . of terminals at the end of a cable or a wire harness; of plugs; of sockets, e.g. wall sockets or power sockets in appliances

31/70 . . . Testing of connections between components and printed circuit boards (G01R 31/68 takes precedence)

31/71 . . . . . . Testing of solder joints

31/72 . . . Testing of electric windings (testing of transformers G01R 31/62)

**WARNING**

Group G01R 31/72 is impacted by reclassification into group G01R 31/62.

Groups G01R 31/72 and G01R 31/62 should be considered in order to perform a complete search.

31/74 . . . Testing of fuses

33/00 **Arrangements or instruments for measuring magnetic variables**

33/0005 . . . [Geometrical arrangement of magnetic sensor elements; Apparatus combining different magnetic sensor types (G01R 33/0026 takes precedence)]

33/0011 . . . [comprising means, e.g. flux concentrators, flux guide, for guiding or concentrating the magnetic flux, e.g. to the magnetic sensor]

33/0017 . . . [Means for compensating offset magnetic fields or the magnetic flux to be measured; Means for generating calibration magnetic fields]

33/0023 . . . [Electronic aspects, e.g. circuits for stimulation, evaluation, control; Treating the measured signals; calibration (G01R 33/0017 takes precedence)]

33/0029 . . . [Treating the measured signals, e.g. removing offset or noise]

33/0035 . . . [Calibration of single magnetic sensors, e.g. integrated calibration]

33/0041 . . . [using feed-back or modulation techniques]

33/0047 . . . [Housings or packaging of magnetic sensors (packaging of semiconductor devices H01L 23/00; Holders)]

33/0052 . . . [Manufacturing aspects; Manufacturing of single devices, i.e. of semiconductor magnetic sensor chips (devices based on galvano-magnetic effect or the like H01L 43/12)]

33/0058 . . . [using bistable elements, e.g. Reed switches]

33/0064 . . . [comprising means for performing simulations, e.g. of the magnetic variable to be measured]

33/007 . . . [Environmental aspects, e.g. temperature variations, radiation, stray fields (G01R 33/025 takes precedence)]

33/0076 . . . . . . [Protection, e.g. with housings against stray fields]

33/0082 . . . . . . [Compensation, e.g. compensating for temperature changes]

33/0088 . . . [use of bistable or switching devices, e.g. Reed switches]

33/0094 . . . [Sensor arrays]

33/02 . . . Measuring direction or magnitude of magnetic fields or magnetic flux (G01R 33/20 takes precedence; measuring direction or magnitude of the earth's field for navigation or surveying G01C; for prospecting, for measuring the magnetic field of the earth G01V 3/00)

**NOTE**

Groups G01R 33/22, G01R 33/10 take precedence over groups G01R 33/025 - G01R 33/09.

33/0206 . . . [Three-component magnetometers]

33/0213 . . . [using deviation of charged particles by the magnetic field]

33/022 . . . Measuring gradient

33/025 . . . Compensating stray fields ((compensating compasses G01C 17/38; G01R 33/0017 takes precedence))

33/028 . . . Electrodynamic magnetometers

33/0283 . . . . . . [in which a current or voltage is generated due to relative movement of conductor and magnetic field]

33/0286 . . . . . . [comprising microelectromechanical systems (MEMS) (MEMS devices in general B81B)]

33/032 . . . using magneto-optic devices, e.g. Faraday [, Cotton-Mouton effect (magneto-optics in general G02E 1/09)]

33/0322 . . . [using the Faraday or Voigt effect]

33/0325 . . . [using the Kerr effect]

33/0327 . . . [with application of magnetostriiction]

33/035 . . . using superconductive devices [manufacture of superconducting elements H01L 39/00]

33/0352 . . . [Superconductive magneto-resistances]

33/0354 . . . [SQUIDS]

33/0356 . . . . . . [with flux feedback]

33/0358 . . . . . . [coupling the flux to the SQUID (gradiometer coils G01R 33/022; coils with superconductive winding H01F 6/06)]

33/038 . . . using permanent magnets, e.g. balances, torsion devices [(electro-dynamic magnetometers G01R 33/028)]
33/0385 . . . [in relation with magnetic force measurements (magnetic force microscopes G01Q 60/50)]
33/04 . . . using the flux-gate principle
33/045 . . . [in single-, or multi-aperture elements]
33/05 . . . in thin-film element
33/06 . . . using galvano-magnetic devices, e.g. Hall effect devices; using magneto-resistive devices (manufacture of galvano-magnetic elements H01L 43/00)
33/063 . . . [Magneto-impedance sensors; Nanocrystallin sensors]
33/066 . . . [field-effect magnetic sensors, e.g. magnetic transistor]
33/07 . . . Hall effect devices
33/072 . . . [Constructional adaptation of the sensor to specific applications]
33/075 . . . . . . (Hall devices configured for spinning current measurements)
33/077 . . . . . . [Vertical Hall-effect devices]
33/09 . . . Magnetoresistive devices
33/091 . . . . . . [Constructional adaptation of the sensor to specific applications]
33/093 . . . . . . [using multilayer structures, e.g. giant magnetoresistance sensors (thin magnetic films H01F 10/00)]
33/095 . . . . . . [extraordinary magnetoresistance sensors]
33/096 . . . . . . [anisotropic magnetoresistance sensors]
33/098 . . . . . . [comprising tunnel junctions, e.g. tunnel magnetoresistance sensors]
33/10 . . . Plotting field distribution (Measuring field distribution)
33/12 . . . Measuring magnetic properties of articles or specimens of solids or fluids (involving magnetic resonance G01R 33/20; using magnetic-optic devices G01R 33/032)
33/1207 . . . [Testing individual magnetic storage devices, e.g. records carriers or digital storage elements (functional testing G06F 11/00; G06F 11/28)]
33/1215 . . . [Measuring magnetisation; Particular magnetometers therefor (G01R 33/14 takes precedence; electrodynamic magnetometers G01R 33/028)]
33/1223 . . . [Measuring permeability, i.e. permeameters (G01R 33/14 takes precedence)]
33/123 . . . [Measuring loss due to hysteresis (G01R 33/14 takes precedence)]
33/1238 . . . [Measuring superconductive properties]
33/1246 . . . [Measuring critical current]
33/1253 . . . [Measuring galvano-magnetic properties]
33/1261 . . . [using levitation techniques]
33/1269 . . . [of molecules labeled with magnetic beads (magnetic particles for bio assay G01N 33/54326)]
33/1276 . . . [of magnetic particles, e.g. imaging of magnetic nanoparticles (G01R 33/1269 takes precedence)]
33/1284 . . . [Spin resolved measurements; Influencing spins during measurements, e.g. in spintronics devices (G01R 33/093 takes precedence; semiconductor devices using spin polarized carriers H01L 29/66084)]
33/1292 . . . [Measuring domain wall position or domain wall motion]
33/14 . . . Measuring or plotting hysteresis curves (G01R 33/1207 takes precedence)
of the coil to the receiver
Electrical details, e.g. matching or coupling
or interpolation
or processing of the MR signal such as
digital down converter, means for analog
modulation of the MR signal using a
rf waveform generators, e.g. frequency
generators, amplitude-, frequency- or
phase modulators or shifters, pulse
programmers, digital to analog converters
for the rf signal, means for filtering or
attenuating of the rf signal
rf power amplifiers
rf receivers or demodulators, e.g.
preamplifiers, means for frequency
modulation of the mr signal using a
digital down converter, means for analog
to digital conversion (adc) or for filtering
or processing of the mr signal such as
bandpass filtering, resampling, decimation
or interpolation
(tuning/matching of the transmit/receive
coil)
(Manufacture of rf coils, e.g. using
printed circuit board technology;
additional hardware for providing
mechanical support to the rf coil
assembly or to part thereof, e.g. a support
for moving the coil assembly relative to
the remainder of the mr system)
(Temperature-controlled rf coils)
(Means for cooling of the rf coils,
e.g. a refrigerator or a cooling vessel
specially adapted for housing an rf
coil)
(Loopless coils, i.e. linear wire antennas)
(Volume type coils, e.g. bird-cage coils;
Quadrature bird-cage coils; Circularly
polarised coils)
(Solenoid coils; Toroidal coils)
(Helmholtz coils)
(Saddle coils)
(Birdcage coils)
(Implantable coils or coils being
generically adaptable to the sample, e.g.
flexible coils or coils comprising mutually
movable parts)
(Rf coils specially adapted for nmr
spectrometers)
(comprising surface coils)
(comprising arrays of sub-coils, i.e.
phased-array coils with fileiple receiver
channels)
of slotted-tube or loop-gap type
of waveguide type (go1r 33/343 takes
precedence)
(Transverse electromagnetic [tem] coils)
(Stripline resonators)
(Electrical details, e.g. matching or coupling
of the coil to the receiver
 rf waveform generators, e.g. frequency
generators, amplitude-, frequency- or
phase modulators or shifters, pulse
programmers, digital to analog converters
for the rf signal, means for filtering or
attenuating of the rf signal)
(rf power amplifiers)
(nmr receivers or demodulators, e.g.
preamplifiers, means for frequency
modulation of the mr signal using a
digital down converter, means for analog
to digital conversion (adc) or for filtering
or processing of the mr signal such as
bandpass filtering, resampling, decimation
or interpolation)
(Tuning/matching of the transmit/receive
coil)
(Multi-frequency operation)
(Mutual coupling or decoupling of
multiple coils, e.g. decoupling of a receive
coil from a transmission coil, or intentional
coupling of rf coils, e.g. for rf magnetic
field amplification)
(Decoupling of multiple rf coils
wherein the multiple rf coils have the
same function in mr, e.g. decoupling
of a receive coil from another receive
coil in a receive coil array, decoupling
d of a transmission coil from another
transmission coil in a transmission coil
array)
(Decoupling of multiple rf coils
wherein the multiple rf coils do not
have the same function in mr, e.g.
decoupling of a transmission coil from a
receive coil)
(Switching for purposes other than coil
coupling or decoupling, e.g. switching
between a phased array mode and a
quadrature mode, switching between
surface coil modes of different geometrical
shapes, switching from a whole body
reception coil to a local reception coil
or switching for automatic coil selection
in moving table mr or for changing
the field-of-view (go1r 33/3671 takes
precedence)
(involving modulation of the quality
factor of the rf coil (go1r 33/3642 takes
precedence)
(involving quadrature drive or detection,
e.g. a circularly polarized rf magnetic
field)
(Means for reducing sheath currents, e.g.
rf traps, baluns)
(involving signal transmission without
using electrically conductive connections,
e.g. wireless communication or optical
communication of the mr signal or an
auxiliary signal other than the mr signal)
(Systems for generation, homogenisation or
stabilisation of the main or gradient magnetic
field)
(Manufacture or installation of magnet
assemblies; Additional hardware for
transportation or installation of the magnet
assembly or for providing mechanical
support to components of the magnet
assembly)
(Additional hardware for cooling or heating
of the magnet assembly, for housing a cooled
or heated part of the magnet assembly or for
temperature control of the magnet assembly)
(Open magnet assemblies for improved
access to the sample, e.g. c-type or u-type
magnets)
(Magnet assemblies for single-sided mr
wherein the magnet assembly is located
on one side of a subject only; Magnet
assemblies for inside-out mr, e.g. for mr
in a borehole or in a blood vessel, or magnet
assemblies for fringe-field mr)
33/381 . . . . using electromagnets (electromagnets per se 
H01F 7/00)
33/3815 . . . . . with superconducting coils, e.g. power 
supply therefor (superconducting magnets
H01F 6/00)
33/383 . . . . using permanent magnets (permanent 
magnets per se H01F 7/02)
33/385 . . . . using gradient magnetic field coils
33/3852 . . . . . (Gradient amplifiers; means for 
controlling the application of a gradient 
magnetic field to the sample, e.g. a 
gradient signal synthesizer)
33/3854 . . . . . (means for active and/or passive vibration 
damping or acoustical noise suppression in 
gradient magnet coil systems)
33/3856 . . . . . (Means for cooling the gradient coils or 
thermal shielding of the gradient coils)
33/3858 . . . . . (Manufacture and installation of gradient 
coops, means for providing mechanical 
support to parts of the gradient-coil 
assembly (manufacture of inductances or 
coils in general H01F 41/00)
33/387 . . . . Compensation of inhomogeneities (screening 
G01R 33/42)
33/3873 . . . . . using ferromagnetic bodies (; Passive 
shimming)
33/3875 . . . . . using correction coil assemblies, e.g. 
active shimming
33/389 . . . . . Field stabilisation, e.g. by field 
measurements and control means or 
indirectly by current stabilisation)
33/42 . . . . . Screening (screening in general H05K 9/00)
33/421 . . . . . of main or gradient magnetic field
33/4215 . . . . . (of the gradient magnetic field, e.g. using 
passive or active shielding of the gradient 
magnetic field)
33/422 . . . . . of the radio frequency field
33/44 . . . . . using nuclear magnetic resonance [NMR] 
(G01R 33/24, G01R 33/62 take precedence)
33/441 . . . . . [Nuclear Quadrupole Resonance [NQR] 
Spectroscopy and Imaging]
33/443 . . . . . [Assessment of an electric or a magnetic field, 
e.g. spatial mapping, determination of a B0 
drift or dosimetry]
33/445 . . . . . [MR involving a non-standard magnetic field 
B0, e.g. of low magnitude as in the earth’s 
magnetic field or in nanoTesla spectroscopy, 
comprising a polarizing magnetic field for pre-
polarisation, B0 with a temporal variation of 
its magnitude or direction such as field cycling 
of B0 or rotation of the direction of B0, or 
spatially inhomogeneous B0 like in fringe-field 
MR or in stray-field imaging]
33/446 . . . . . [Multifrequency selective RF pulses, e.g. 
multinuclear acquisition mode (spatially 
selective RF pulses G01R 33/4833)]
33/448 . . . . . [Relaxometry, i.e. quantification of relaxation 
times or spin density (G01R 33/50 takes 
precedence)]
33/46 . . . . . NMR spectroscopy
33/4608 . . . . . [RF excitation sequences for enhanced 
detection, e.g. NOE, polarisation transfer, 
selection of a coherence transfer pathway]
33/4616 . . . . . [using specific RF pulses or specific 
modulation schemes, e.g. stochastic 
excitation, adiabatic RF pulses, composite 
pulses, binomial pulses, Shinnar-le-Roux 
pulses, spectrally selective pulses not being 
used for spatial selection]
33/4625 . . . . . [Processing of acquired signals, e.g. 
elimination of phase errors, baseline fitting, 
chemometric analysis]
33/463 . . . . . [Sequences for multi-dimensional NMR]
33/4641 . . . . . [Sequences for NMR spectroscopy of 
samples with ultrashort relaxation times such 
as solid samples]
33/465 . . . . . applied to biological material, e.g. in vitro 
testing
33/48 . . . . . NMR imaging systems
33/4802 . . . . . [Travelling-wave MR]
33/4804 . . . . . [Spatially selective measurement of 
temperature or pH]
33/4806 . . . . . [Functional imaging of brain activation]
33/4808 . . . . . [Multimodal MR, e.g. MR combined with 
positron emission tomography [PET], MR 
combined with ultrasound or MR combined 
with computed tomography [CT]]
33/481 . . . . . [MR combined with positron emission 
tomography [PET] or single photon 
emission computed tomography [SPECT]]
33/4812 . . . . . [MR combined with X-ray or computed 
tomography [CT]]
33/4814 . . . . . [MR combined with ultrasound]
33/4816 . . . . . [NMR imaging of samples with ultrashort 
relaxation times such as solid samples, e.g. 
MRI using ultrashort TE [UTE], single point 
image imaging, constant time imaging]
33/4818 . . . . . [MR characterised by data acquisition 
along a specific k-space trajectory or by the 
temporal order of k-space coverage, e.g. 
centric or segmented coverage of k-space]
33/482 . . . . . [using a Cartesian trajectory]
33/4822 . . . . . . [in three dimensions]
33/4824 . . . . . [using a non-Cartesian trajectory]
33/4826 . . . . . . [in three dimensions]
33/4828 . . . . . [Resolving the MR signals of different 
chemical species, e.g. water-fat imaging]
33/483 . . . . . . with selection of signals or spectra from 
particular regions of the volume, e.g. in vivo 
spectroscopy
33/4831 . . . . . [using B1 gradients, e.g. rotating frame 
techniques, use of surface coils]
33/4833 . . . . . . [using spatially selective excitation of 
the volume of interest, e.g. selecting non-
orthogonal or inclined slices]
33/4835 . . . . . . [of multiple slices]
33/4836 . . . . . [using an RF pulse being spatially 
selective in more than one spatial 
dimension, e.g. a 2D pencil-beam 
excitation pulse]
33/4838 . . . . . [using spatially selective suppression or 
saturation of MR signals]
33/485 . . . . . based on chemical shift information [CSI 
or spectroscopic imaging, e.g. to acquire 
the spatial distributions of metabolites]
based on the determination of relaxation times [e.g. T1 measurement by IR sequences; T2 measurement by multiple-echo sequences]

Signal processing systems, e.g. using pulse sequences [e.g. Generation or control of pulse sequences (in general H01K); Operator Console]

(Control of the operation of the MR system, e.g. setting of acquisition parameters prior to or during MR data acquisition, dynamic shimming, use of one or more scout images for scan plane prescription (G01R 33/546 takes precedence)

[Interface between the MR system and the user, e.g. for controlling the operation of the MR system or for the design of pulse sequences]

Image enhancement or correction, e.g. subtraction or averaging techniques [e.g. improvement of signal-to-noise ratio and resolution (image data processing in general G06T)]

(by filtering or weighting based on different relaxation times within the sample, e.g. T1 weighting using an inversion pulse)

[Microscopy; Zooming]

(by transferring coherence or polarization from a spin species to another, e.g. creating magnetization transfer contrast [MTC], polarization transfer using nuclear Overhauser enhancement [NOE])

(by reducing the NMR signal of a particular spin species, e.g. of a chemical species for fat suppression, or of a moving spin species for black-blood imaging)

[Data processing and visualization specially adapted for MR, e.g. for feature analysis and pattern recognition on the basis of measured MR data, edge contour detection on the basis of measured MR data, for enhancing measured MR data in terms of signal-to-noise ratio by means of noise filtering or apodization, for enhancing measured MR data in terms of resolution by means for deblurring, windowing, zero filling, or generation of gray-scaled images, colour-coded images or images displaying vectors instead of pixels (image data processing or generation, in general G06T)]

(by reduction of the scanning time, i.e. fast acquiring systems, e.g. using echo-planar pulse sequences]

[Parallel magnetic resonance imaging, e.g. sensitivity encoding [SENSE], simultaneous acquisition of spatial harmonics [SASH], unaliasing by Fourier encoding of the overlaps using the temporal dimension [UNFOLD], k-t-broad-use linear acquisition speed-up technique [k-t-BLAST], k-t-SENSE (structural details of arrays of sub-coils G01R 33/3415)]

[Parallel RF transmission, i.e. RF pulse transmission using a plurality of independent transmission channels]

[Generating steady state signals, e.g. low flip angle sequences [FLASH]]

(by using a fully balanced steady-state free precession [bSSFP] pulse sequence, e.g. trueFISP]

[Echo train techniques involving acquiring plural, differently encoded, echo signals after one RF excitation, e.g. using gradient refocusing in echo planar imaging [EPI], RF refocusing in rapid acquisition with relaxation enhancement [RARE] or using both RF and gradient refocusing in gradient and spin echo imaging [GRASE]]

(by using gradient refocusing, e.g. EPI]

(by using RF refocusing, e.g. RARE]

(by using both RF and gradient refocusing, e.g. GRASE]

(by temporal sharing of data, e.g. keyhole, block regional interpolation scheme for k-Space [BRIK])

(of moving material, e.g. flow contrast angiography]

[Characterization of motion or flow; Dynamic imaging]

(involving phase contrast techniques]

(Cine imaging]

(Involving spatial modulation of the magnetization within an imaged region, e.g. spatial modulation of magnetization [SPAMM] tagging (perfusion imaging based on arterial spin tagging G01R 33/5636)]

(Diffusion imaging]

(Angiography, e.g. contrast-enhanced angiography [CE-MRA] or time-of-flight angiography [TOF-MRA]]

(Elastography]

(Perfusion imaging]

(Intentional motion of the sample during MR, e.g. moving table imaging]

(involving motion of the sample as a whole, e.g. multistation MR or MR with continuous table motion)
[involving motion of a part of the sample with respect to another part of the sample, e.g. MRI of active joint motion]

Correction of image distortions, e.g. due to magnetic field inhomogeneities

[due to motion, displacement or flow, e.g. gradient moment nulling (G01R 33/567 takes precedence)]

[due to eddy currents, e.g. caused by switching of the gradient magnetic field]

NOTE
This group only covers correction of artifacts caused by gradient-nonlinearity

[due to chemical shift effects]

[due to magnetic susceptibility variations]

[caused by finite or discrete sampling, e.g. Gibbs ringing, truncation artefacts, phase aliasing artefacts]

[caused by acquiring plural, differently encoded echo signals after one RF excitation, e.g. correction for readout gradients of alternating polarity in EPI]

[caused by a distortion of the main magnetic field B0, e.g. temporal variation of the magnitude or spatial inhomogeneity of B0 (G01R 33/56509, G01R 33/56518, G01R 33/56536 take precedence)]

[caused by a distortion of a gradient magnetic field, e.g. non-linearity of a gradient magnetic field (G01R 33/56509, G01R 33/56518, G01R 33/56536 take precedence)]

[due to Maxwell fields, i.e. concomitant fields]

[caused by a distortion of the RF magnetic field, e.g. spatial inhomogeneities of the RF magnetic field (G01R 33/56509, G01R 33/56518, G01R 33/56536 take precedence)]

[gated by physiological signals, i.e. synchronization of acquired MR data with periodical motion of an object of interest, e.g. monitoring or triggering system for cardiac or respiratory gating]

[Gating or triggering based on a physiological signal other than an MR signal, e.g. ECG gating or motion monitoring using optical systems for monitoring the motion of a fiducial marker]

[Gating or triggering based on an MR signal, e.g. involving one or more navigator echoes for motion monitoring and correction]

Calibration of imaging systems, e.g. using test probes, Phantoms; Calibration objects or fiducial markers such as active or passive RF coils surrounding an MR active material]

[Calibration of signal excitation or detection systems, e.g. for optimal RF excitation power or frequency (G01R 33/246 takes precedence)]

[for optimal flip angle of RF pulses]

. using electron paramagnetic resonance (G01R 33/24, G01R 33/62 take precedence)

. using double resonance (G01R 33/24 takes precedence)

. using cyclotron resonance (G01R 33/24 takes precedence {Omegatrons per se H01J 49/38])

Testing or calibrating of apparatus covered by the preceding groups (G01R 33/31901 takes precedence)

. of cathode ray oscilloscopes

. [Calibrating; Standards or reference devices, e.g. voltage or resistance standards, "golden" references (G01R 33/0035, G01R 35/002 take precedence)]

. [Standards or reference devices, e.g. voltage or resistance standards, "golden references"]

. of auxiliary devices, e.g. of instrument transformers according to prescribed transformation ratio, phase angle, or wattage rating

. of instruments for measuring time integral of power or current

. by stroboscopic methods